



STRUCTURAL STUDIES OF MULTIFERROIC THIN FILMS

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Collaborating with:

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Professor Amlan Biswas

Daniel Grant



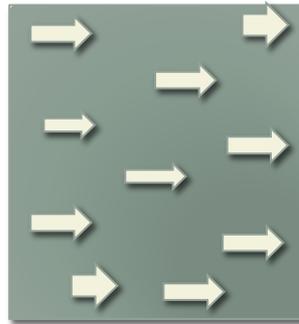
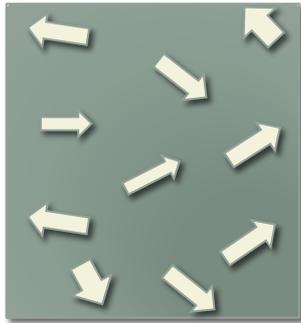
NCNR



<http://www.ncnr.nist.gov/instruments/dcs/>

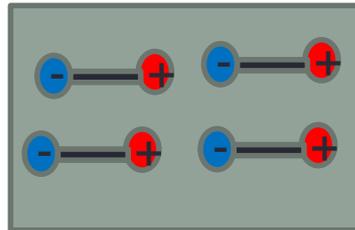
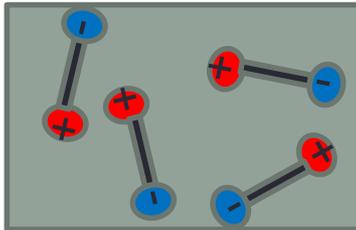
Ferroicity

Ferromagnetism



H

Ferroelectricity



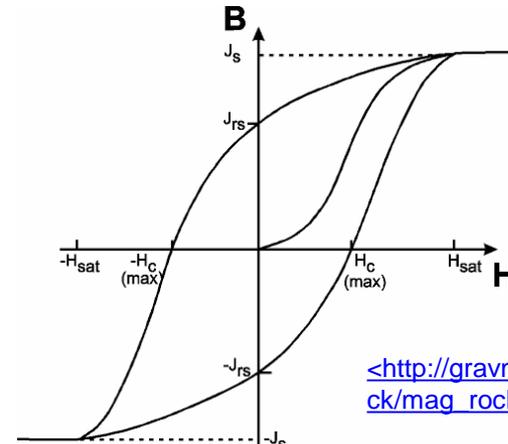
E

Magnetoelectric

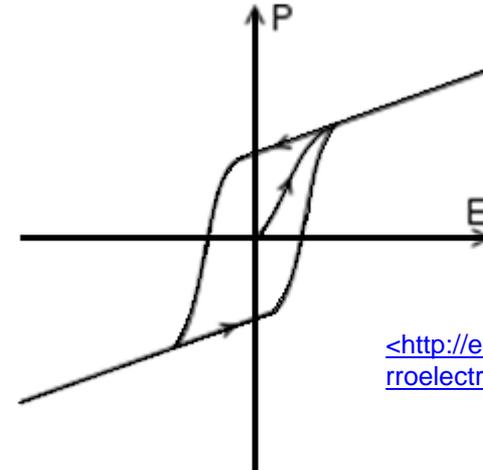
$$\alpha_{\eta\xi} / 4\pi < (\chi_{\eta\eta} \kappa_{\xi\xi})^{1/2}.$$

$\chi_{\eta\eta}$: Magnetic Susceptibility Tensor

$\kappa_{\xi\xi}$: Electric Susceptibility Tensor



http://gravmag.ou.edu/mag_rock/mag_rock.html



<http://en.wikipedia.org/wiki/Ferroelectricity>

Perovskite Structure (ABO_3)



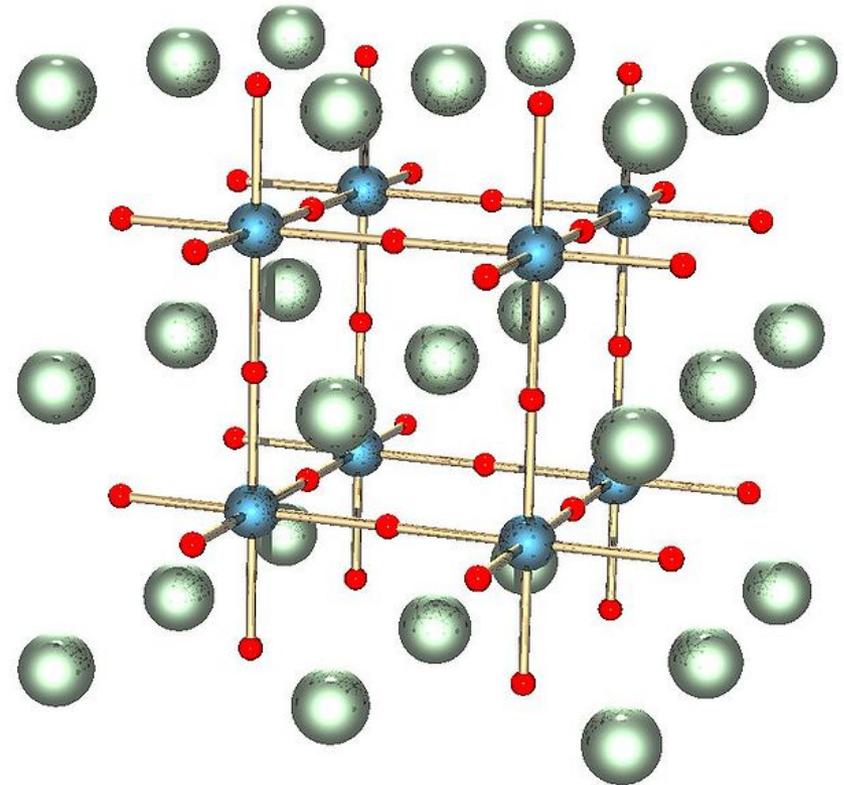
A-Site Atoms



B-Site Atoms



Oxygen Atoms

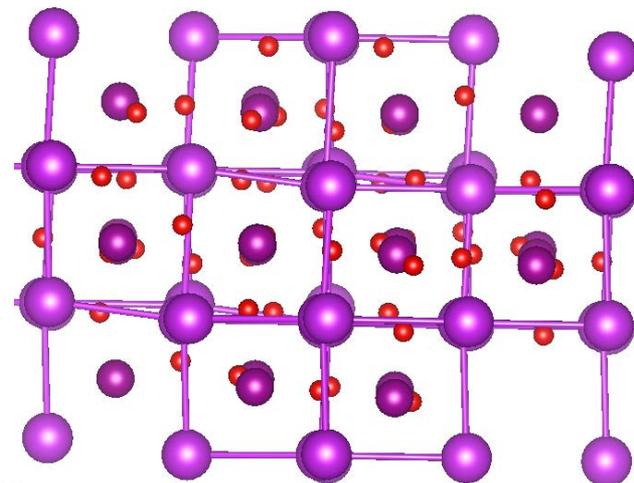


[<http://en.wikipedia.org/wiki/Perovskite_\(structure\)>](http://en.wikipedia.org/wiki/Perovskite_(structure))

BiMnO₃

- Distorted perovskite structure.
- Multiferroic (Magnetoelectric).

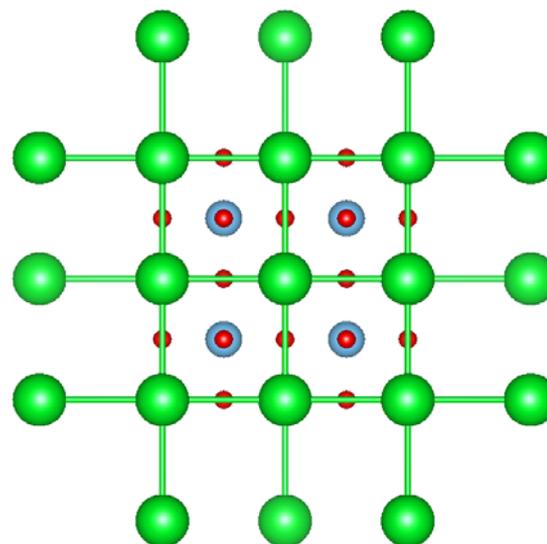
Boukhvalov, D.W.; Solovyev, I.V. *Phys. Rev. Serie 3. B – Cond. Matt.* **82**, (2010) 245101-1.



SrTiO₃ (Substrate)

- Perovskite structure.

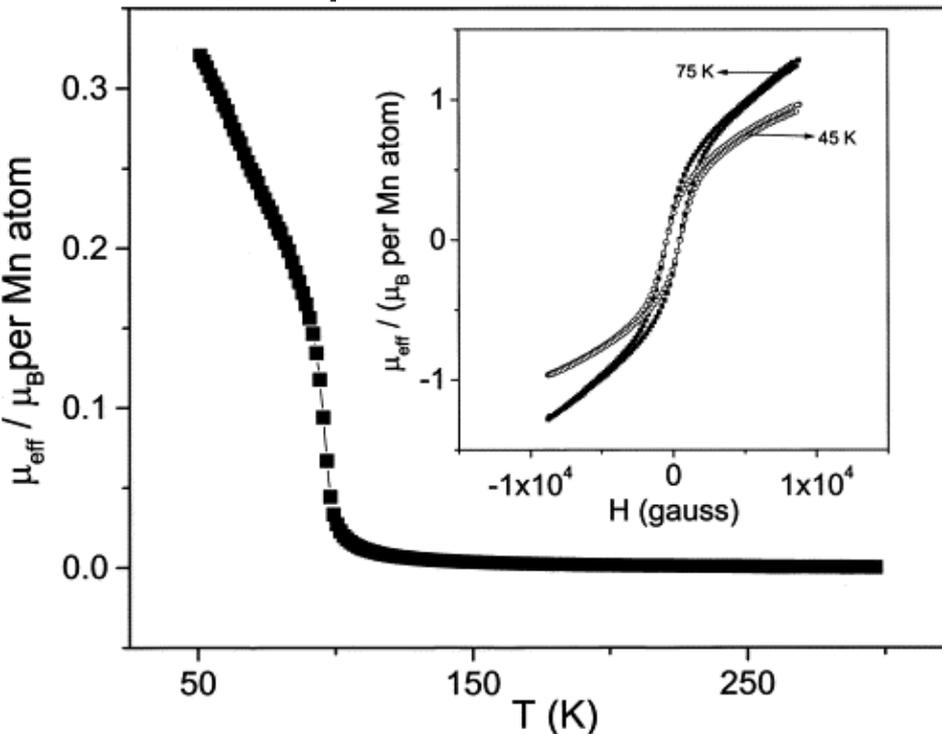
Brous, J.; Fankuchen, I.; Banks, E. *Acta Cryst.* **6**, (1953) 67-70.



[K. Momma and F. Izumi, "VESTA 3 for three-dimensional visualization of crystal, volumetric and morphology data," *J. Appl. Crystallogr.*, 44, 1272-1276 \(2011\).](#)

Bulk (Powder) BiMnO₃

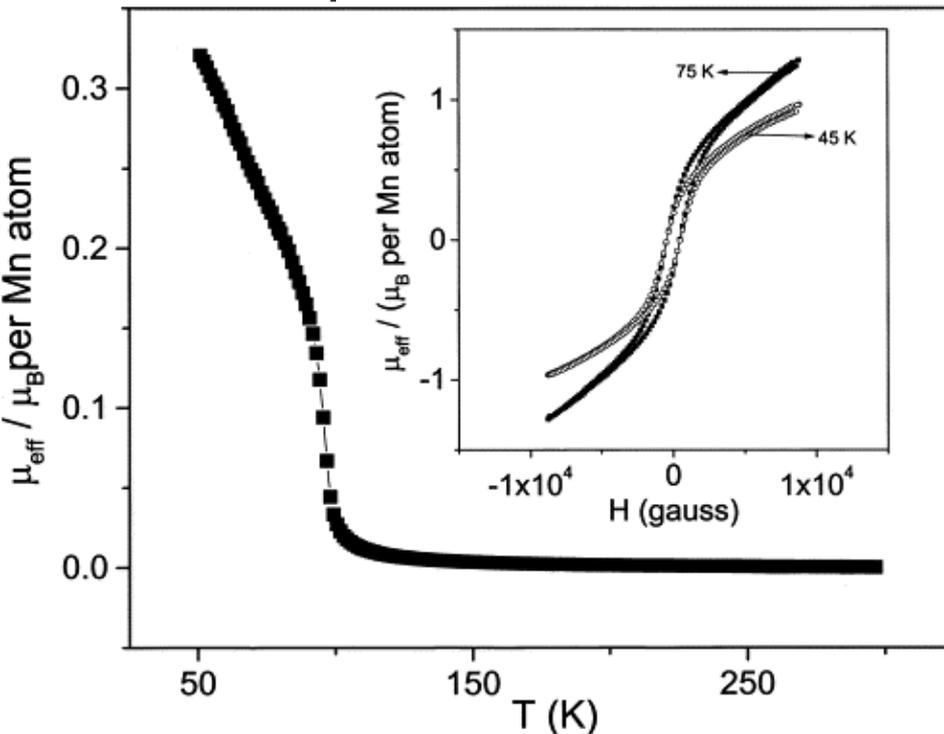
- 3GPa, 1100K for synthesis.
- M_{sat} = 3.6 μ_B/Mn at 5 K
- T_c = 105 K
- P_s = 62 μC/cm² at 87K



A. Moreira dos Santos, S. Parashar, A.R. Raju, Y.S. Zhao, A.K. Cheetham, C.N.R. Rao, **Solid State Commun.** **122**, (2002)

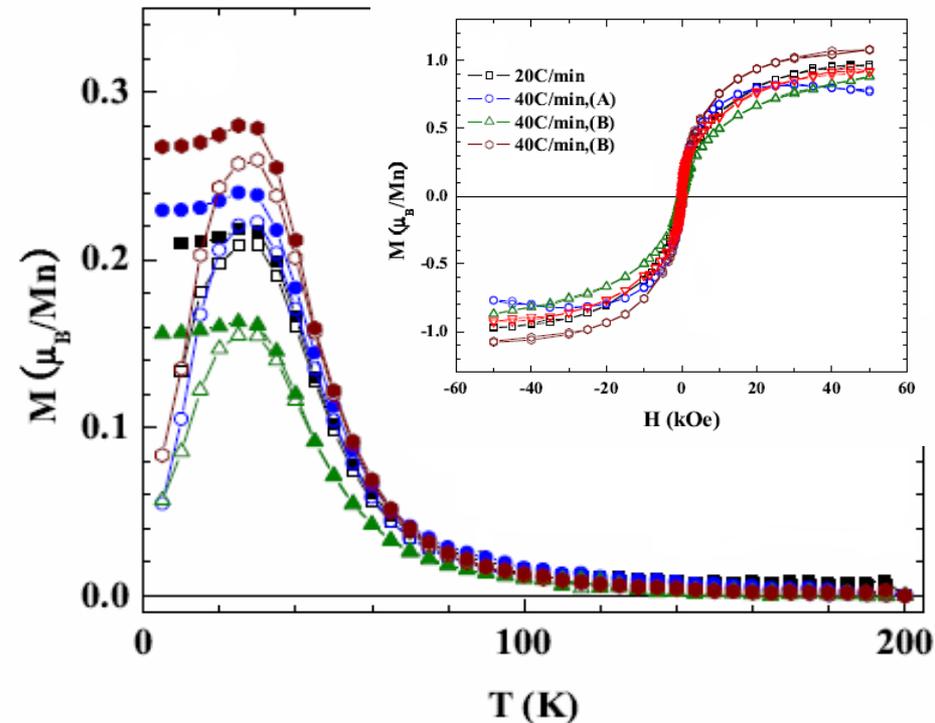
Bulk (Powder) BiMnO₃

- 3GPa, 1100K for synthesis.
- Msat = 3.6 μ_B /Mn at 5 K
- Tc = 105 K
- Ps = 62 $\mu\text{C}/\text{cm}^2$ at 87K



Film BiMnO₃

- Pulsed Laser Deposition.
- Msat = 1 μ_B /Mn at 5 K
- Tc = reduced / smeared
- Ps = 16 $\mu\text{C}/\text{cm}^2$ at 87K

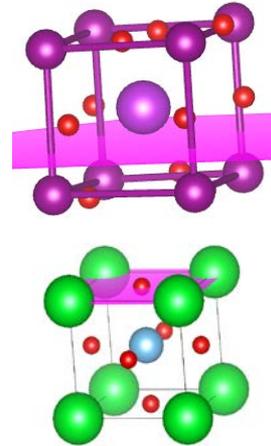


Why is there a difference between the bulk and the film form of BiMnO_3 ?

Hypotheses

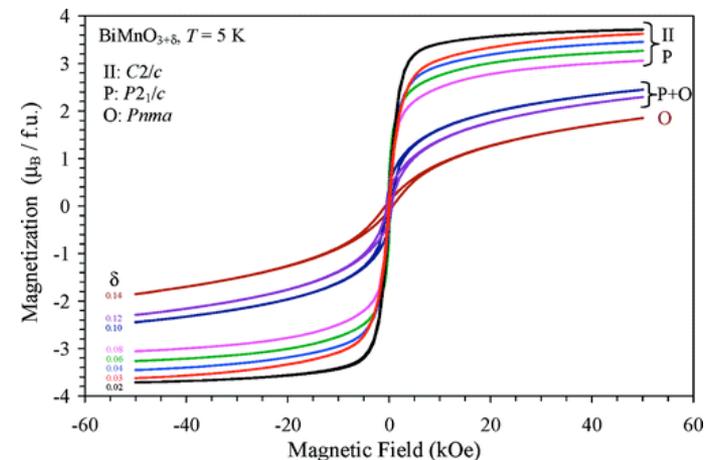
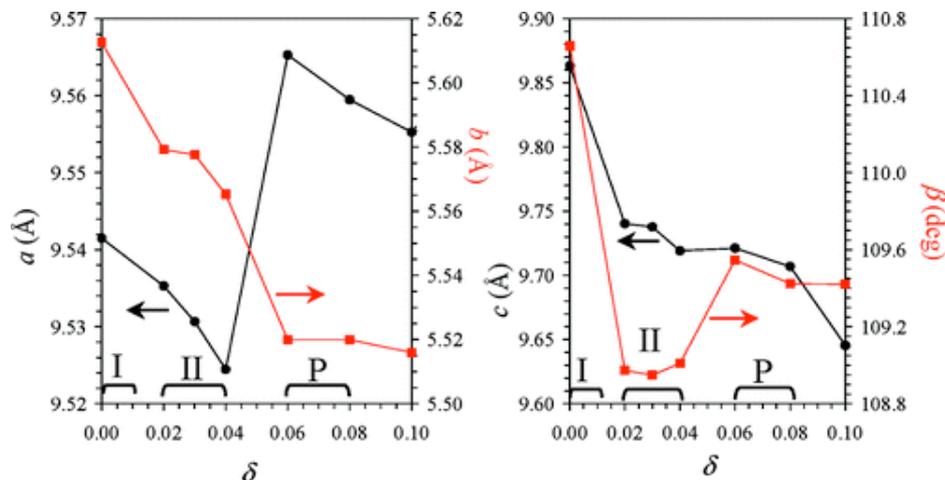
1. Strain from substrate

- 1 0 0 SrTiO_3 plane binds with 1 1 1 BiMnO_3 plane
- Magnetic moment reduced from change in geometric shape.



2. Unstoichiometric composition

- Magnetic Properties dependent on stoichiometry ($\text{BiMnO}_{3+\delta}$)
 - Magnetic moment is reduced with increased oxygen content.
 - Requires Polarized Neutron Reflectivity to find the magnetic moment as a function of depth.



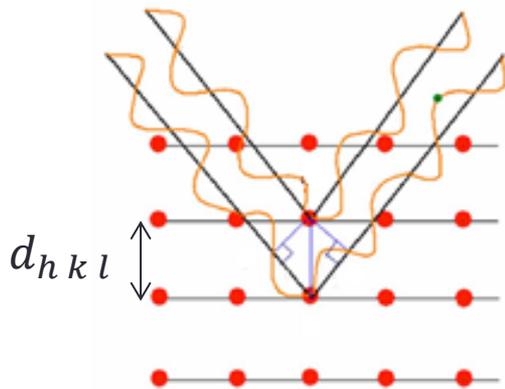
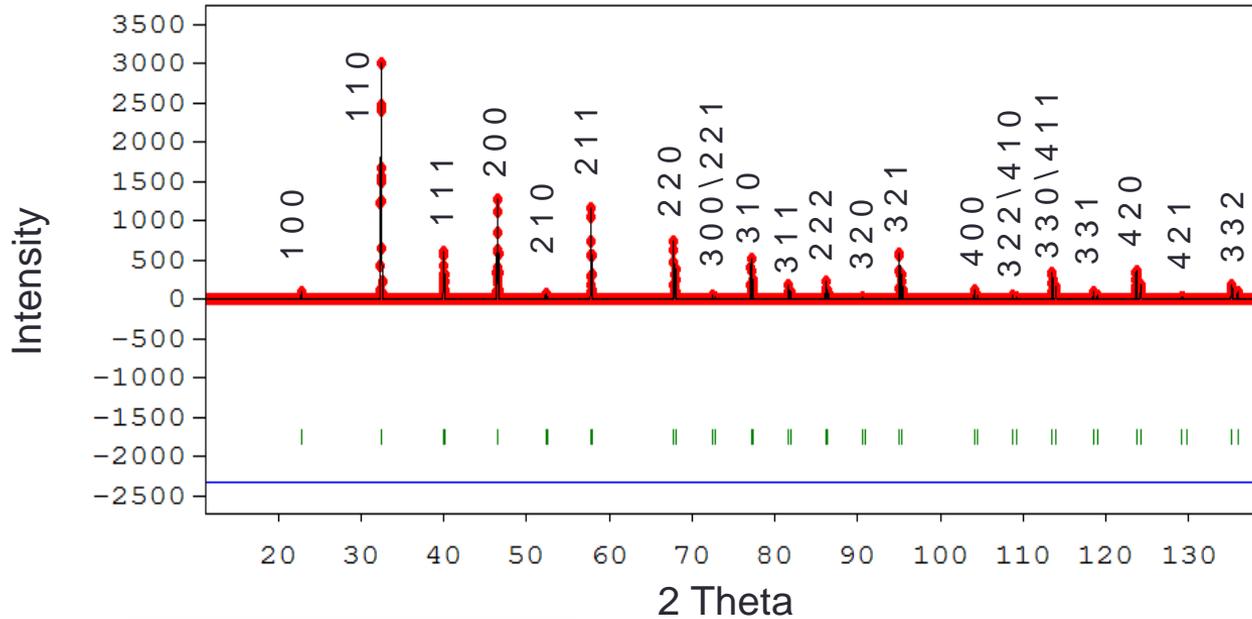


Attacking the Problem

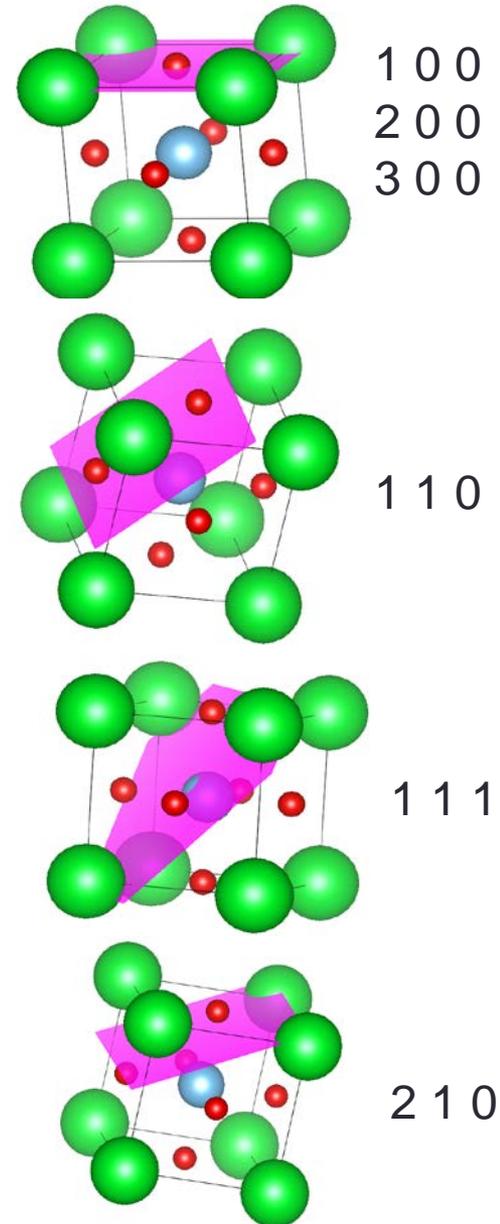
- Diffraction
 - Growth orientation
 - Lattice parameters
- Atomic Force Microscopy
 - Surface roughness
- Reflectometry
 - Roughness
 - Thickness
 - Density as a function of depth.
- X-Ray Photoelectron Spectroscopy
 - Atomic composition as a function of depth

X-Ray Diffraction

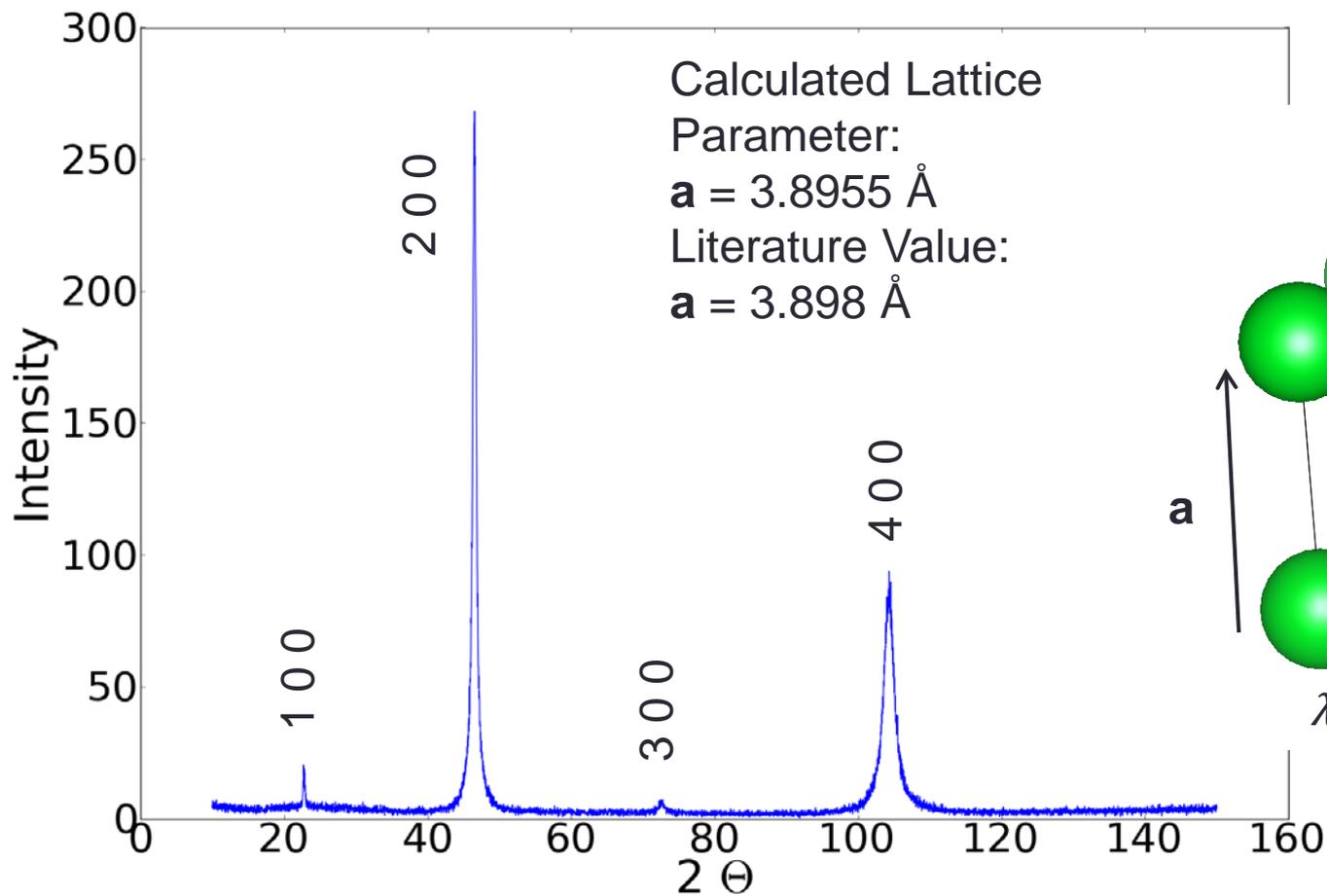
Powder Diffraction Peaks of SrTiO₃



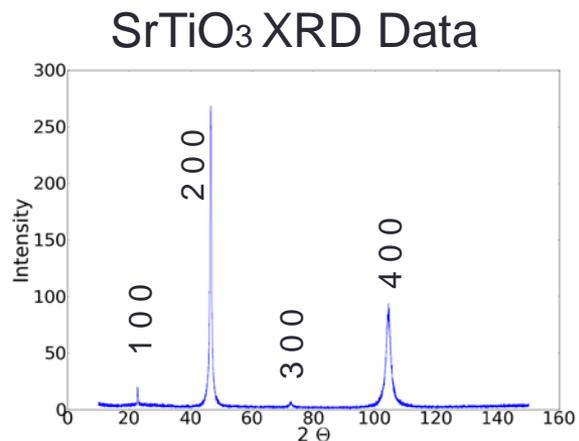
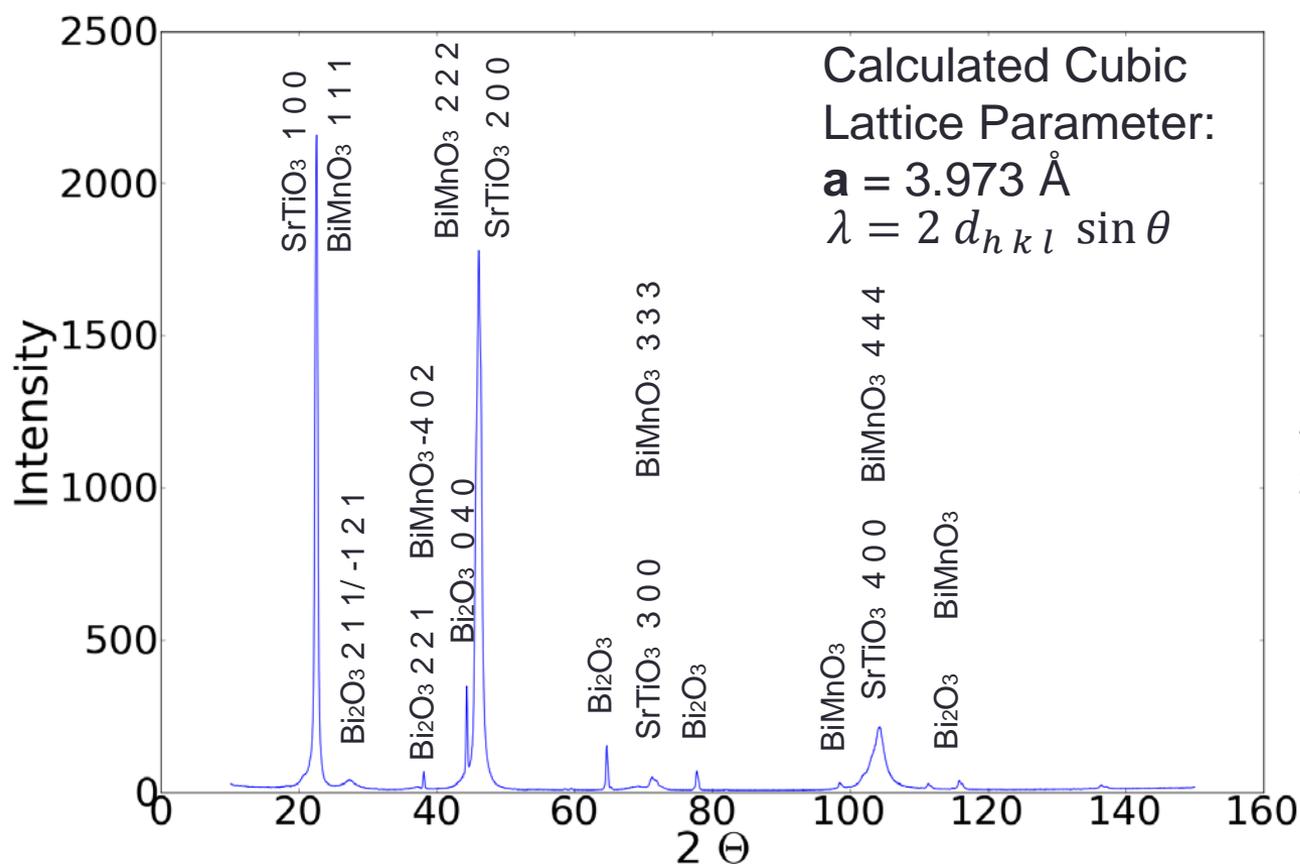
$$\lambda = 2 d_{hkl} \sin \theta$$



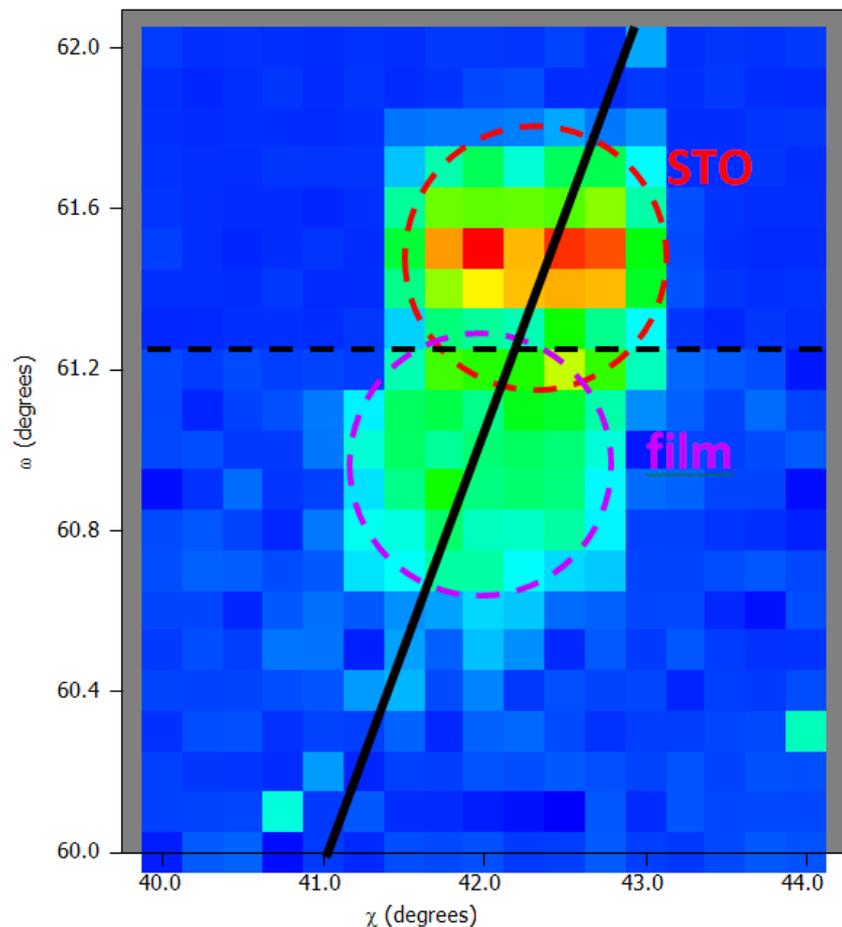
SrTiO₃ X-ray Diffraction (XRD) Data



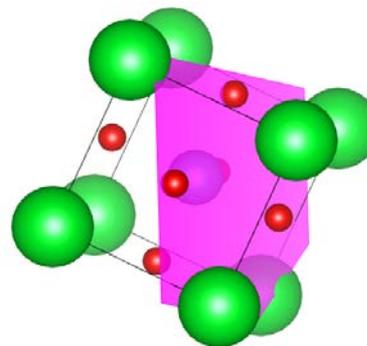
BiMnO₃ X-ray Diffraction Data



X-Ray Diffraction Mesh Scan



- $\{2\ 1\ 1\}$ SrTiO₃ Plane



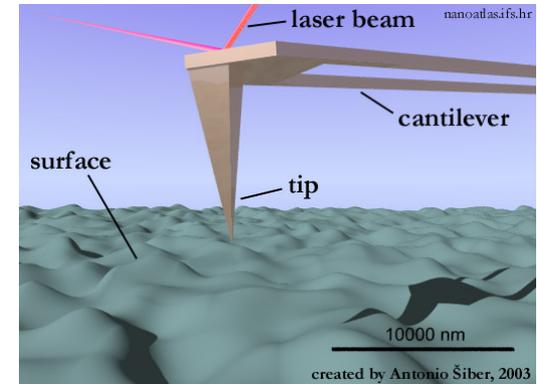
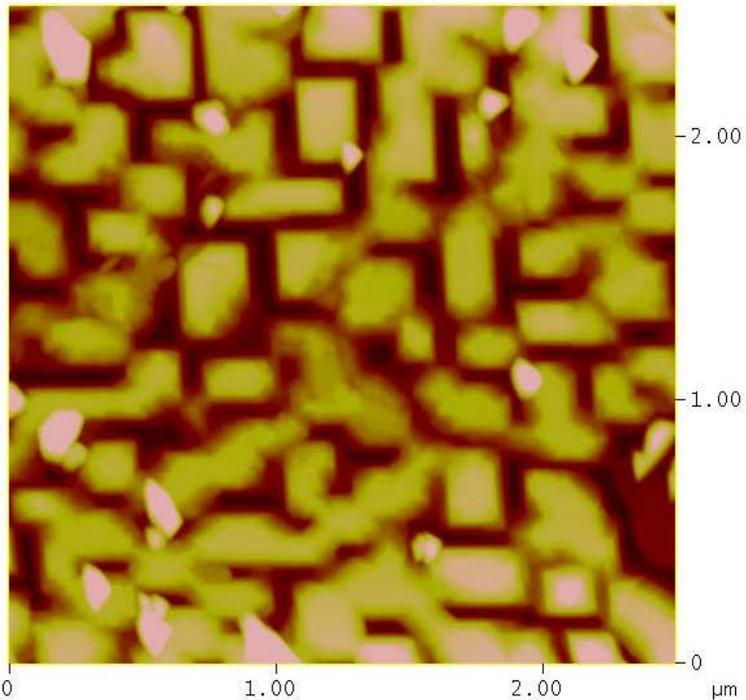
- Rocking Curves:

$$\lambda = 2 d_{hkl} \sin \theta$$

- $a_{\text{SrTiO}_3} = 3.898 \text{ \AA}$
(literature)
- $a_{\text{BiMnO}_3} = 3.946 \text{ \AA}$ in plane
(calculated)
 - Elongated out of plane.
- Epitaxial Growth.

Atomic Force Microscopy

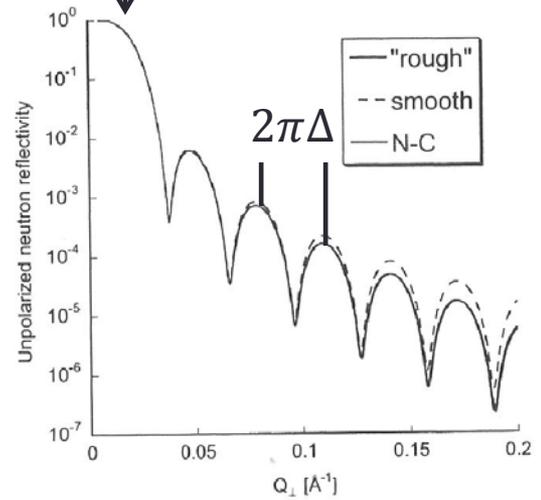
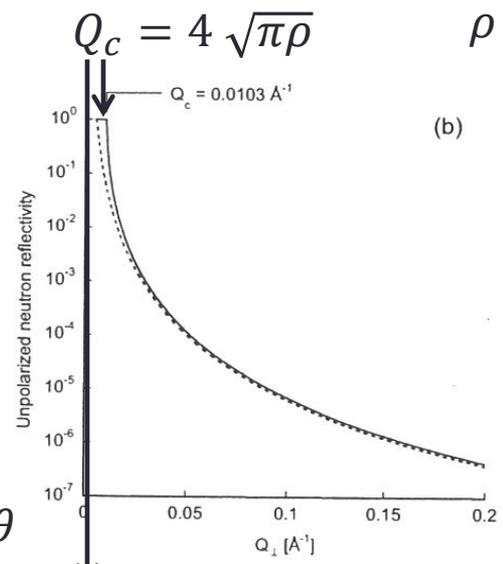
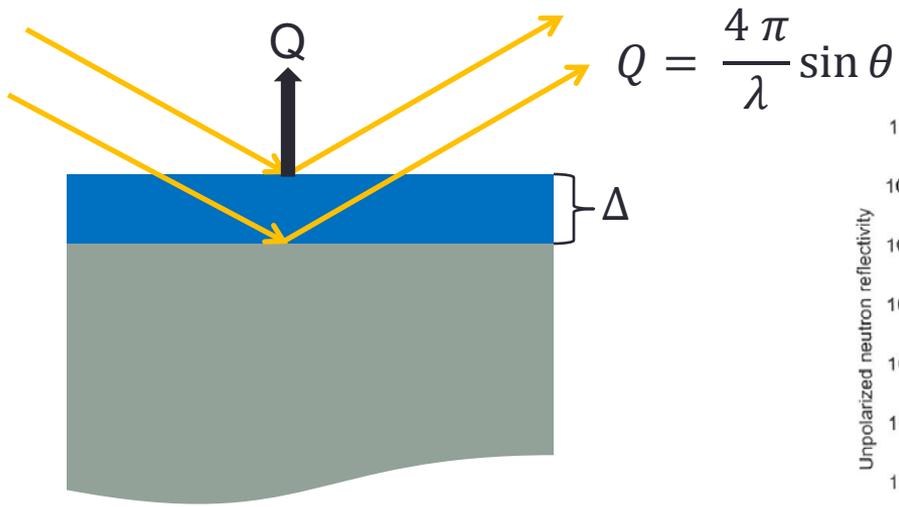
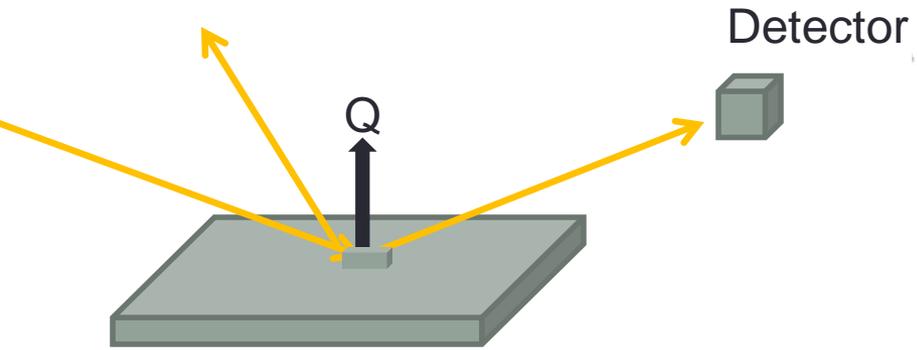
Roughness Analysis



http://www.nanotech-now.com/Art_Gallery/antonio-siber.htm

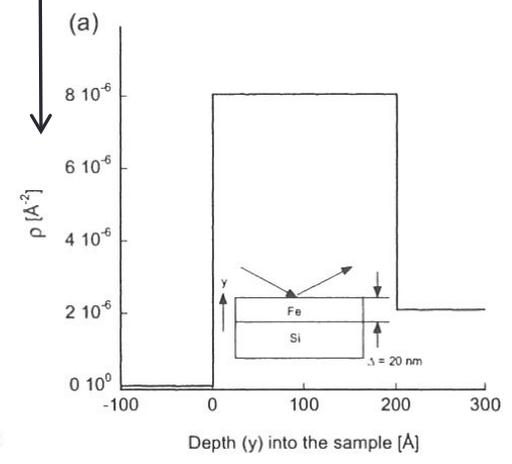
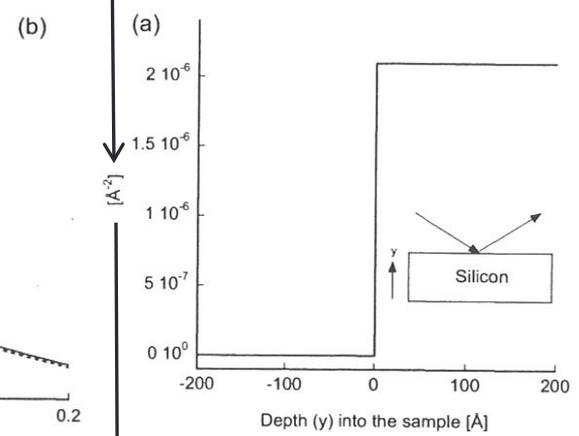
Crevices are calculated to make up 20% of the sample.

Reflectometry



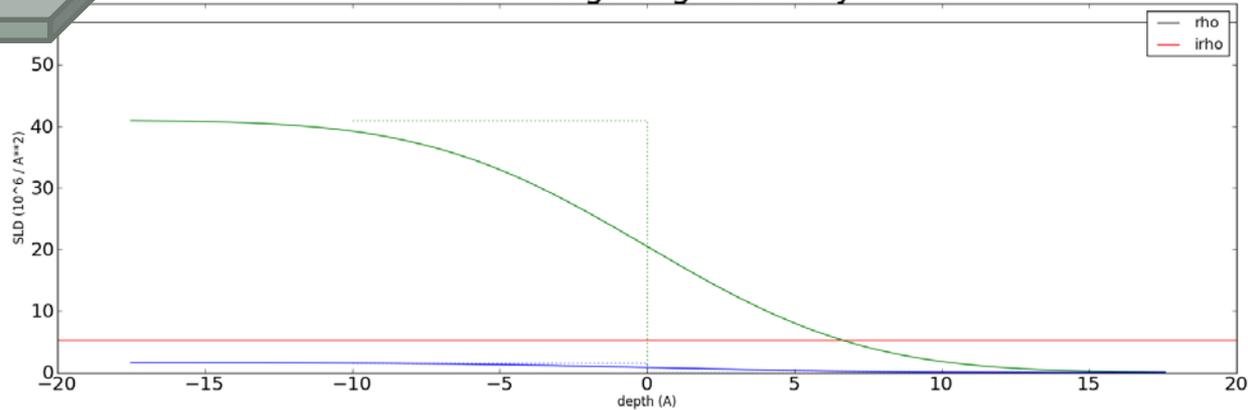
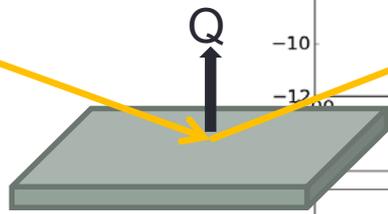
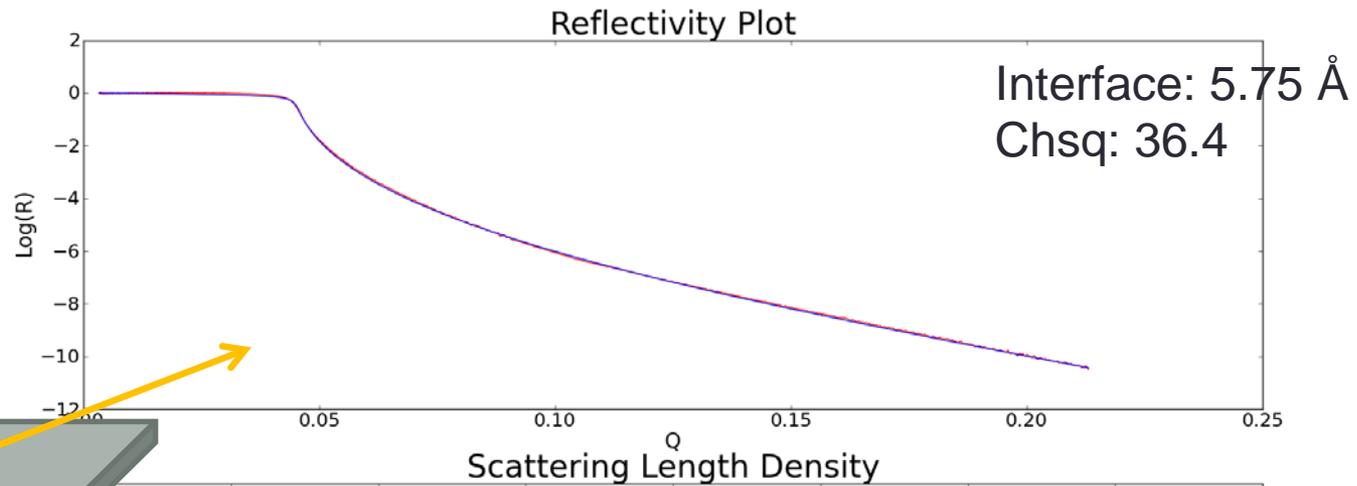
$$\rho = \frac{\sum_{i=1}^n b_c}{V_m}$$

$$\rho = \frac{\sum_{i=1}^n Z r_e}{V_m}$$

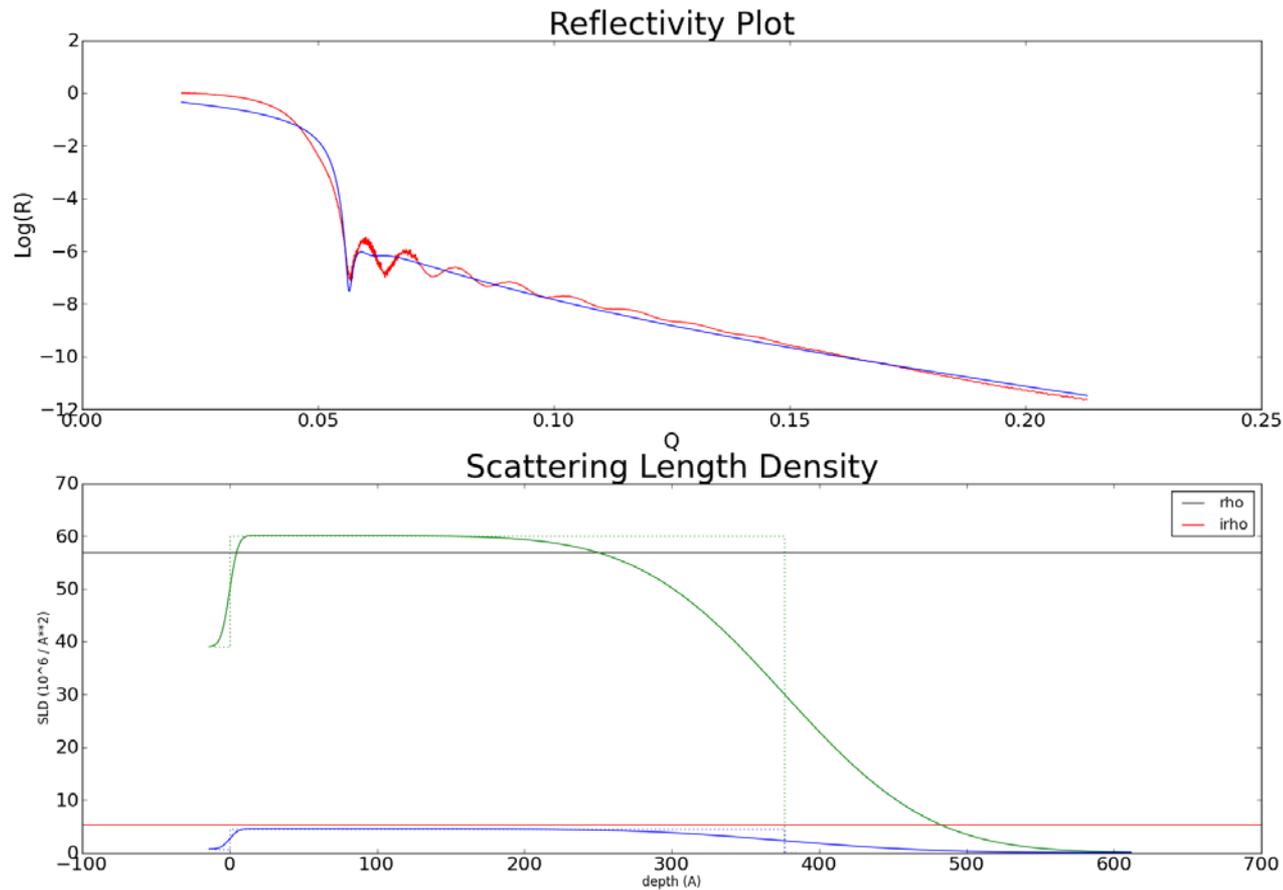


“Modern Techniques for Characterizing Magnetic Materials.” Ed. By Yimei Zhu. Kluwer Acad. Publishers (2005).

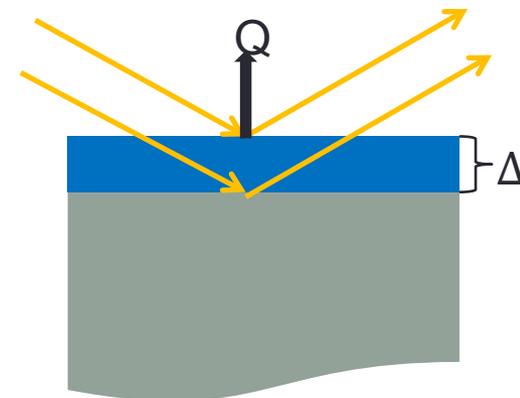
SrTiO₃ X-ray Reflectometry Data



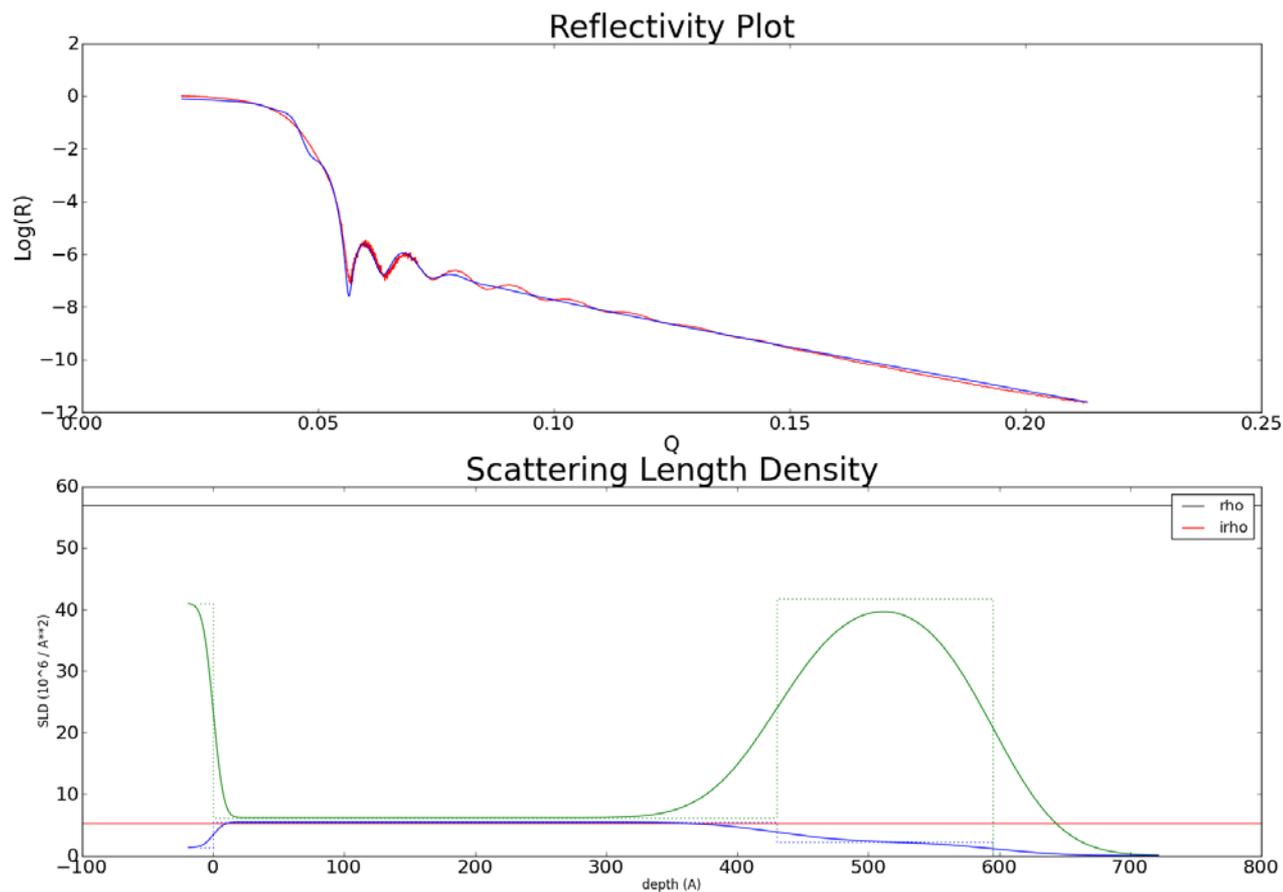
BiMnO₃ X-ray Reflectometry Data



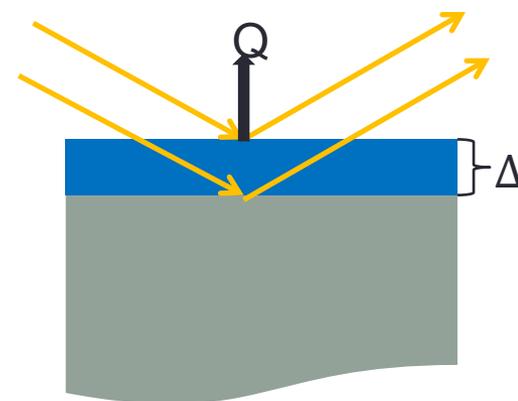
1 Layer of BiMnO₃
Chsq: 271.5
Thickness: 376 \AA
Interface: 78.4 \AA



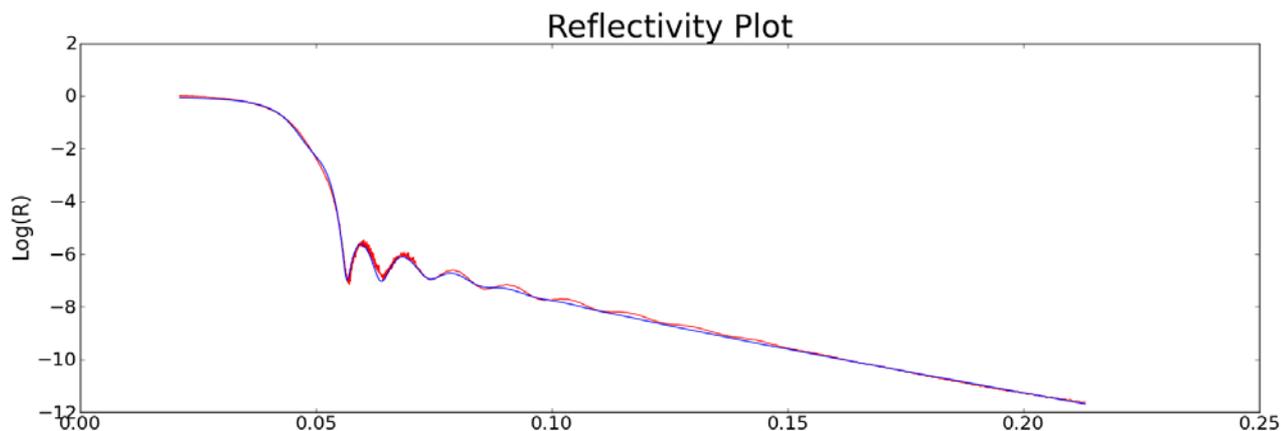
BiMnO₃ X-ray Reflectometry Data



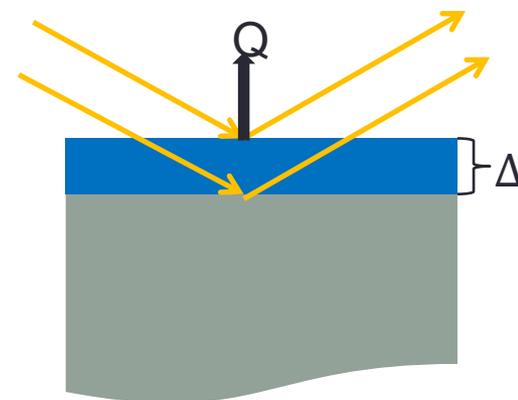
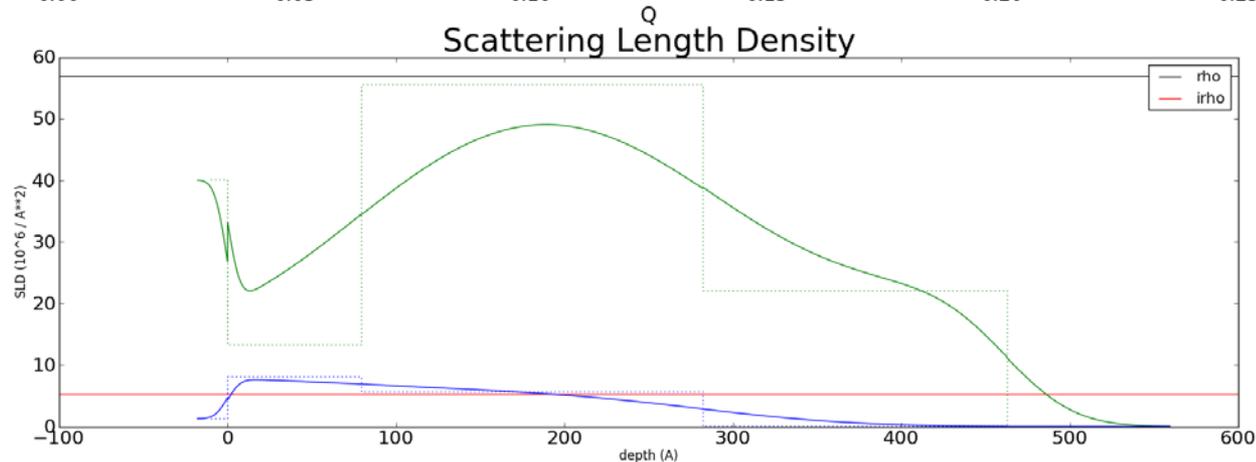
2 Layers of BiMnO₃
Chsq: 181.3
Total thickness: 594.6 \AA
1st Layer thickness: 430 \AA
1st Layer interface: 43.4 \AA
2nd Layer thickness: 164.6 \AA
2nd Layer interface: 42.2 \AA



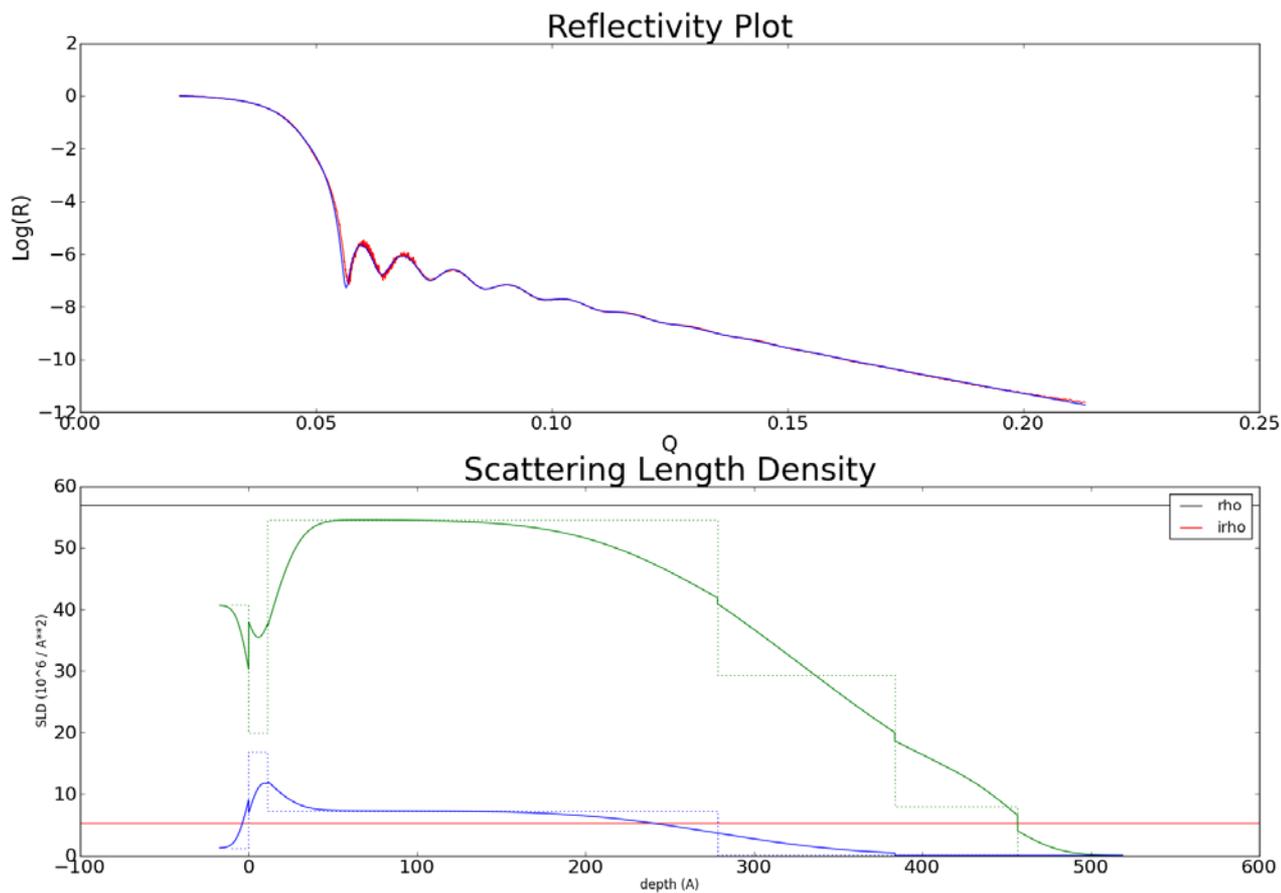
BiMnO₃ X-ray Reflectometry Data



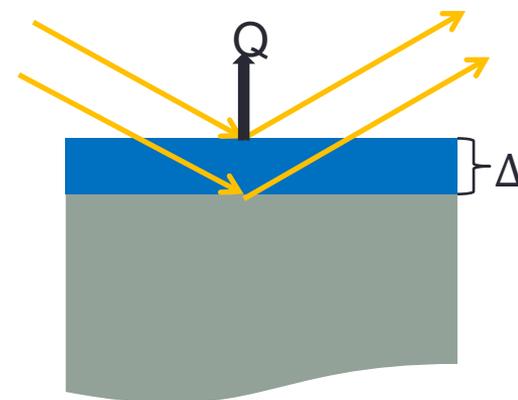
3 Layers of BiMnO₃
Chsq: 85.9
Total thickness: 594.6 Å
1st Layer thickness: 79.7 Å
1st Layer interface: 77.5 Å
2nd Layer thickness: 202.2 Å
2nd Layer interface: 71.4 Å
3rd Layer thickness: 180.7 Å
3rd Layer interface: 32.2 Å



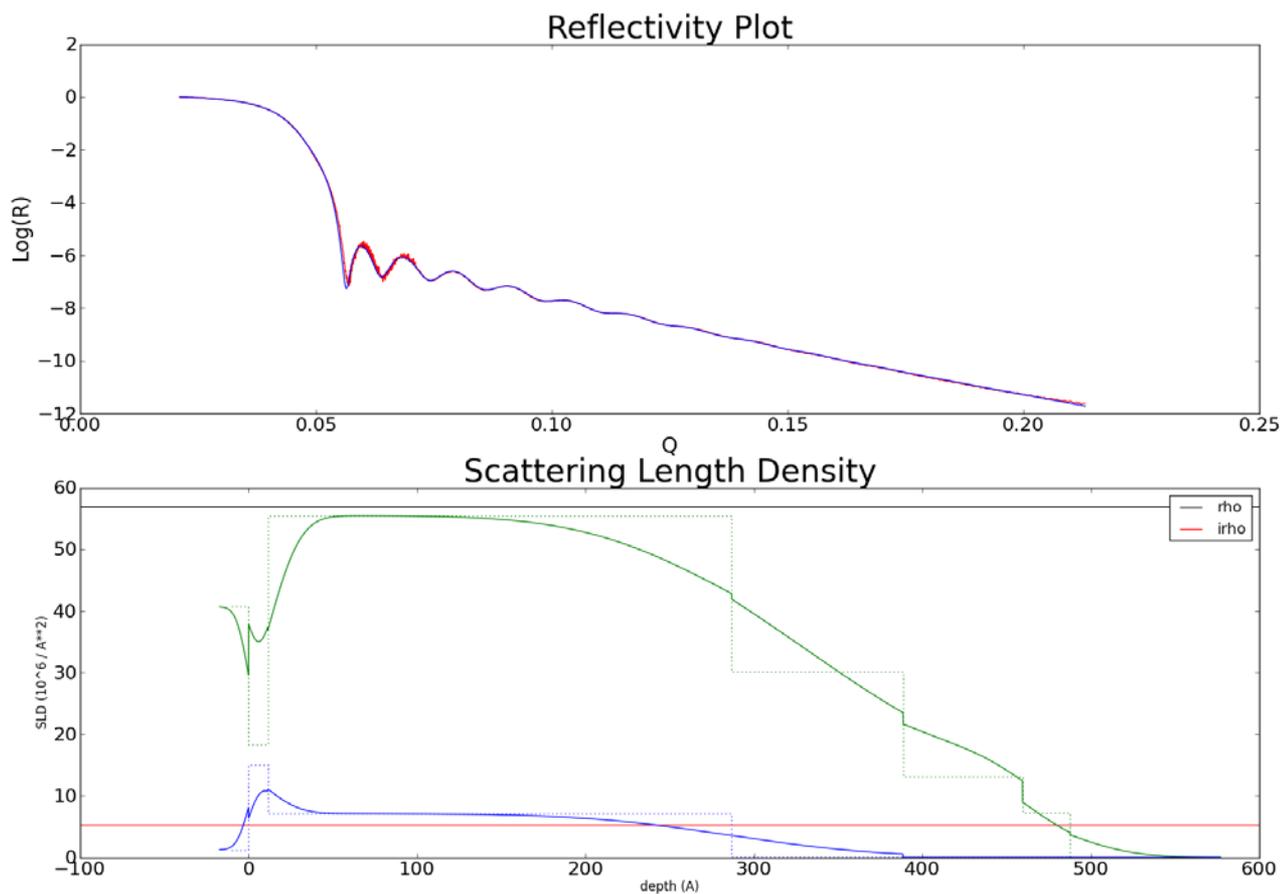
BiMnO₃ X-ray Reflectometry Data



4 Layers of BiMnO₃
Chsq: 36.4
Total thickness: 456.14 \AA
1st Layer thickness: 11.14 \AA
1st Layer interface: 15.04 \AA
2nd Layer thickness: 266.6 \AA
2nd Layer interface: 66.4 \AA
3rd Layer thickness: 102.8 \AA
3rd Layer interface: 61.7 \AA
4th Layer thickness: 75.6 \AA
4th Layer interface: 21.0 \AA



BiMnO₃ X-ray Reflectometry Data



5 Layers of BiMnO₃

Chsq: 35.00

Total thickness: 487.67 \AA

1st Layer thickness: 11.44 \AA

1st Layer interface: 15.15 \AA

2nd Layer thickness: 275.32 \AA

2nd Layer interface: 70.13 \AA

3rd Layer thickness: 101.74 \AA

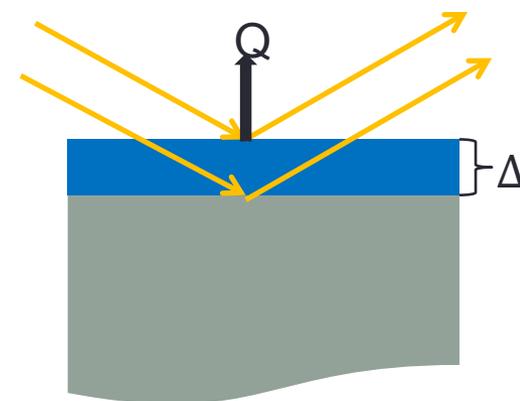
3rd Layer interface: 36.4 \AA

4th Layer thickness: 70.91 \AA

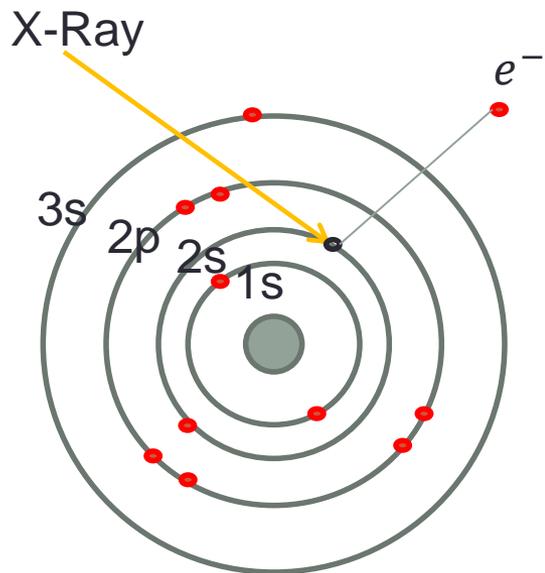
4th Layer interface: 18.9 \AA

5th Layer thickness: 28.26 \AA

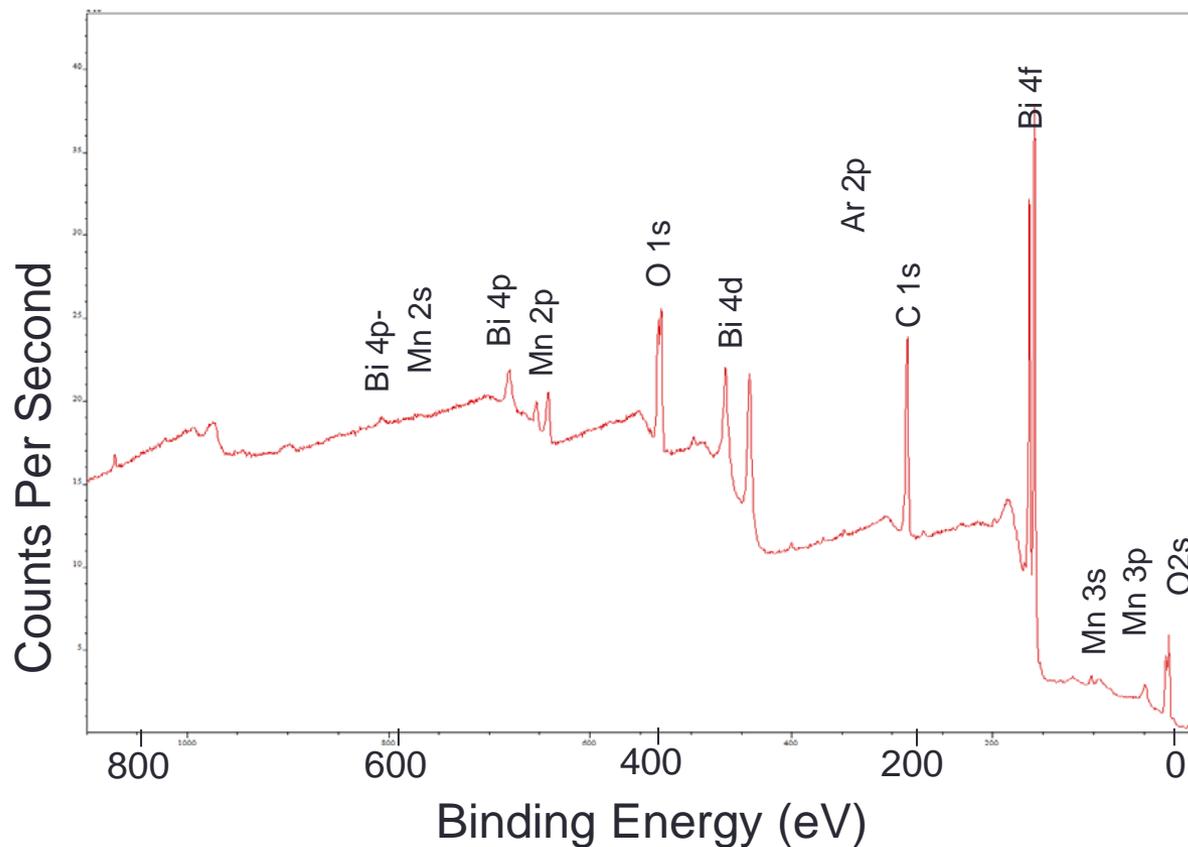
5th Layer interface: 29.76 \AA



X-Ray Photoelectron Spectroscopy



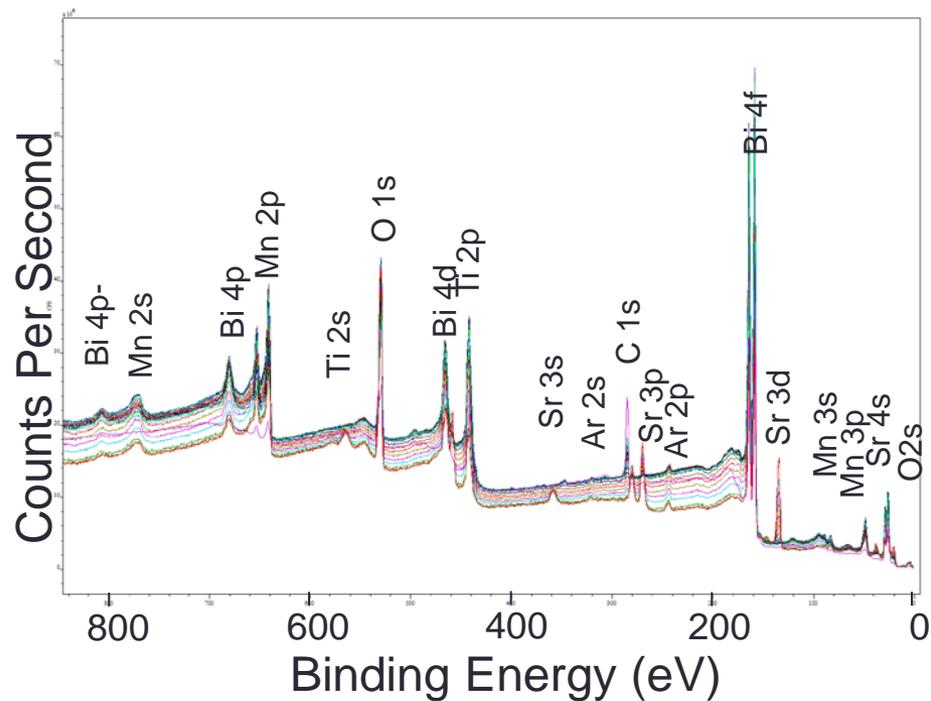
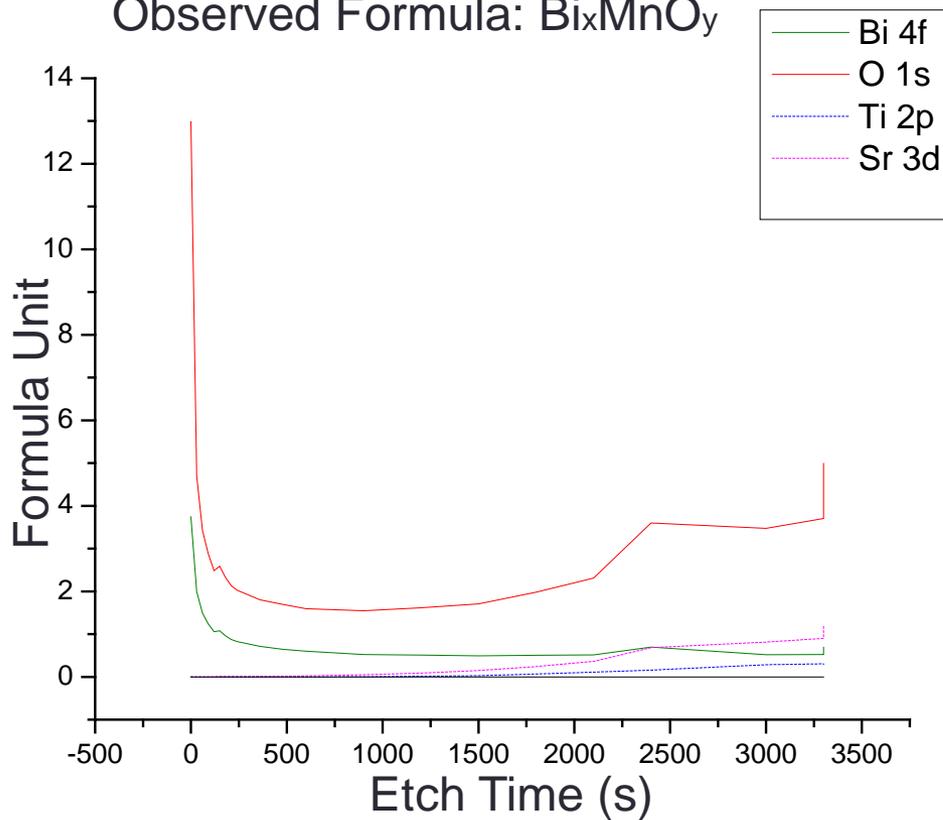
$$KE = h\nu - \text{Binding Energy}$$



X-Ray Photoelectron Spectroscopy

Expect BiMnO_3

Observed Formula: Bi_xMnO_y





Conclusions

- Data suggests unstoichiometric composition of BiMnO_3 .
 - Diffraction: extra peaks show
 - Atomic Force Microscopy: 20% of the surface has voids.
 - Reflectometry: Reduced scattering length density on the surface and at the interface with the SrTiO_3 .
 - Spectroscopy: May have an increase in oxygen content at the substrate. Large concentration of Bismuth and Oxygen at surface.

On Going (Over the next 4 weeks):

- Neutron Reflectometry Data
 - Scattering Length Densities
 - X-Rays (electron density): Bi ~ 83, Mn ~ 25, O ~ 8 (atomic number)
 - Neutrons (nuclear contrast): Bi ~ 8.5, Mn ~ -3.73, O ~ 5.803 (bound coherent scattering lengths)
 - Gives additional information on the chemical formula.
- Polarized Neutron Reflectometry:
 - Calculate magnetic moment as a function of depth.

Acknowledgments

NIST/CHRNS. Julie A. Borchers, Robert D. Shull, and Terrell A. Vanderah (Directors, MML/NCNR Materials Science SURF Program).

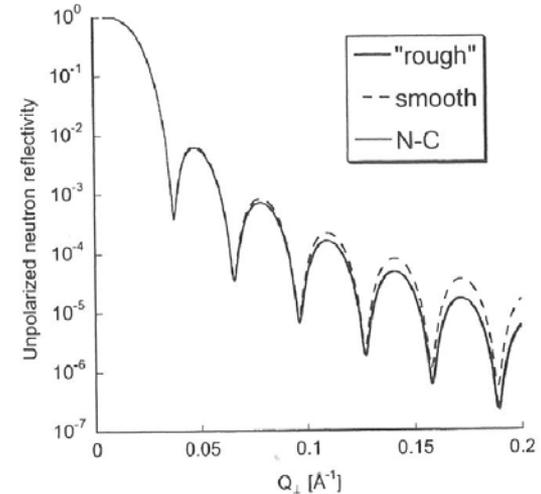
Dan Neumann, Rob Dimeo.

Daniel Pajeroski, Professor Biswas and Daniel Grant.



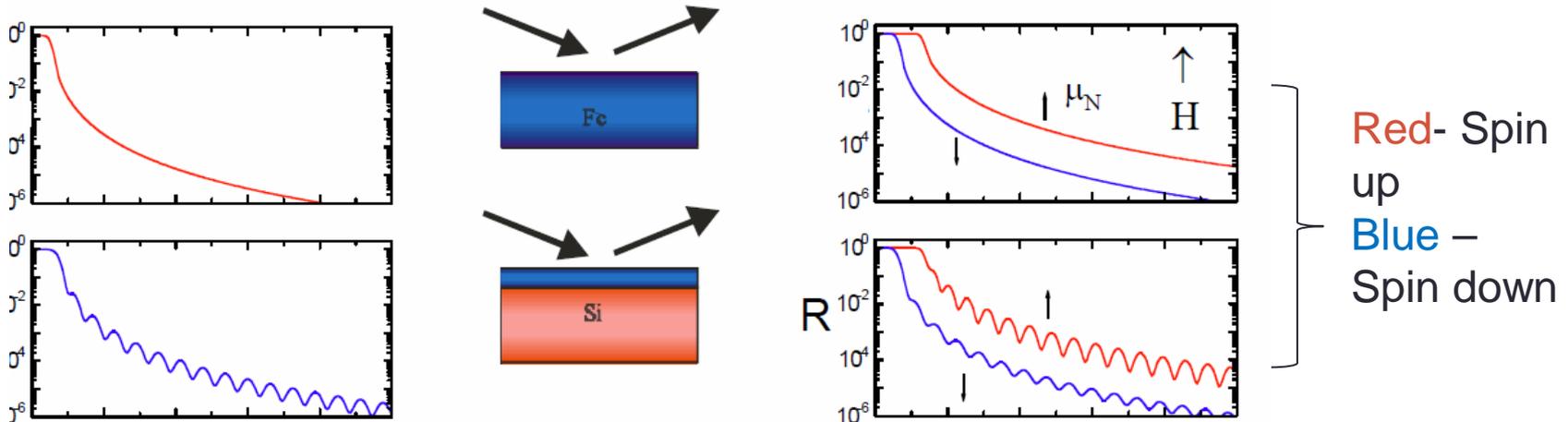
Neutron Reflectometry

- Nuclear and magnetic scattering.



Polarized Neutron Reflectometry

- Separates spin up and spin down.



Roger Pynn. Neutron Reflectometry. Indiana U. and Spallation Neutron Source.

<http://www.che.udel.edu/cns/pdf/Reflectometry.pdf>